

Search Notes

Application/Control No.

10/671,116

Examiner

Sun J. Lin

Applicant(s)/Patent under
Reexamination

SCHIEK, RICHARD

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	19	10/20/2005	JSL
716	21	10/20/2005	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	10/20/2005	JSL
IEEE	10/20/2005	JSL